Special Issue

Digital Image Processing: Advanced Technologies and Applications

Message from the Guest Editors

This Special Issue will focus on digital imaging strategies, with the aim of processing, analyzing, and investigating imaging and all the latest methods involved in handling them. Manuscripts are invited in all these different multidisciplinary areas, but are not limited to them. Recently, interest in computer vision, machine learning, and deep learning has grown significantly. Therefore, manuscripts that explore the utility of such tools in exploring advanced technologies and applications are also encouraged. In this Special Issue, we invite authors to submit original research papers, reviews, and viewpoint articles that are related to recent advances at all levels of the applications and technologies of imaging and signal analysis. We are open to papers that address a diverse range of topics, from foundational issues up to novel algorithms that aim to provide state-of-the-art solutions and technological systems for practical and feasible applications.

Guest Editors

Dr. Zahid Mehmood Jehangiri

Dr. Mohsin Shahzad

Dr. Uzair Khan

Deadline for manuscript submissions

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About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32, 20133 Milano, Italy

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